

from PLUS search

For 10/604582

10804582\_CLSTITLES.txt  
Titles of Most Frequently Occurring Classifications of Patents Returned  
From A Search of 10804582 on March 06, 2006

- 17 714/733 (1 OR, 16 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/733 ..Built-in testing circuit (BILBO)
- 13 714/724 (6 OR, 7 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing
- 10 324/73.1 (3 OR, 7 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/73.1 PLURAL, AUTOMATICALLY SEQUENTIAL TESTS
- 9 324/537 (4 OR, 5 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
ELECTRIC COMPONENTS  
324/537 .Of individual circuit component or element
- 9 714/727 (6 OR, 3 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/726 ..Scan path testing (e.g., level sensitive scan  
design (LSSD))  
714/727 ...Boundary scan
- 8 714/732 (3 OR, 5 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/732 ..Signature analysis
- 8 714/734 (3 OR, 5 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/734 ..Structural (in-circuit test)
- 7 324/754 (2 OR, 5 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
ELECTRIC COMPONENTS  
324/537 .Of individual circuit component or element  
324/754 ..With probe elements
- 6 324/158.1 (5 OR, 1 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/158.1 MISCELLANEOUS
- 5 324/763 (4 OR, 1 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING

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324/500	FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
324/537	.Of individual circuit component or element
324/763	..DUT including test circuit
5 324/765	(0 OR, 5 XR)
Class 324	: ELECTRICITY: MEASURING AND TESTING
324/500	FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
324/537	.Of individual circuit component or element
324/765	..Test of semiconductor device
5 714/726	(4 OR, 1 XR)
Class 714	: ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/724	.Digital logic testing
714/726	..Scan path testing (e.g., level sensitive scan design (LSSD))
5 714/736	(1 OR, 4 XR)
Class 714	: ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/724	.Digital logic testing
714/736	..Device response compared to expected fault-free response
5 714/738	(0 OR, 5 XR)
Class 714	: ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/724	.Digital logic testing
714/738	..Including test pattern generator
4 324/72.5	(1 OR, 3 XR)
Class 324	: ELECTRICITY: MEASURING AND TESTING
324/72	TESTING POTENTIAL IN SPECIFIC ENVIRONMENT (E.G., LIGHTNING STROKE)
324/72.5	.Voltage probe
4 326/16	(2 OR, 2 XR)
Class 326	: ELECTRONIC DIGITAL LOGIC CIRCUITRY
326/16	WITH TEST FACILITATING FEATURE
4 365/201	(3 OR, 1 XR)
Class 365	: STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01	READ/WRITE CIRCUIT
365/201	.Testing
3 702/117	(0 OR, 3 XR)
Class 702	: DATA PROCESSING: MEASURING, CALIBRATING, OR TESTING
702/108	TESTING SYSTEM
702/117	.Of circuit
3 714/718	(0 OR, 3 XR)
Class 714	: ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/718	.Memory testing
3 714/728	(2 OR, 1 XR)

- Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/726 ..Scan path testing (e.g., level sensitive scan  
design (LSSD))  
714/728 ...Random pattern generation (includes  
pseudorandom pattern)
- 3 714/739 (1 OR, 2 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/738 ..Including test pattern generator  
714/739 ...Random pattern generation (includes  
pseudorandom pattern)
- 2 323/311 (0 OR, 2 XR)  
Class 323 : ELECTRICITY: POWER SUPPLY OR REGULATION  
SYSTEMS  
323/304 SELF-REGULATING (E.G., NONRETROACTIVE)  
323/311 .Using a three or more terminal semiconductive  
device as the final control device
- 2 324/522 (0 OR, 2 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
ELECTRIC COMPONENTS  
324/512 .For fault location  
324/522 ..By voltage or current measuring
- 2 324/676 (0 OR, 2 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES  
REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE  
RELATIONSHIPS  
324/649 .Lumped type parameters  
324/658 ..Using capacitive type measurement  
324/676 ...With pulse signal processing circuit
- 2 324/679 (0 OR, 2 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES  
REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE  
RELATIONSHIPS  
324/649 .Lumped type parameters  
324/658 ..Using capacitive type measurement  
324/679 ...With comparison or difference circuit
- 2 324/758 (2 OR, 0 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
ELECTRIC COMPONENTS  
324/537 .Of individual circuit component or element  
324/754 ..With probe elements  
324/758 ...Probe alignment or positioning
- 2 326/39 (0 OR, 2 XR)  
Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY  
326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,  
UNIVERSAL, ETC.)  
326/39 .Array (e.g., PLA, PAL, PLD, etc.)

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- 2 708/252 (1 OR, 1 XR)  
 Class 708 : ELECTRICAL COMPUTERS: ARITHMETIC PROCESSING  
                   AND CALCULATING  
       708/100 ELECTRICAL DIGITAL CALCULATING COMPUTER  
       708/200 .Particular function performed  
       708/250 ..Random number generation  
       708/252 ...Linear feedback shift register
  
- 2 714/25 (0 OR, 2 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
                   DETECTION/RECOVERY  
       714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING  
  
       714/1 .Reliability and availability  
       714/25 ..Fault locating (i.e., diagnosis or testing)
  
- 2 714/32 (0 OR, 2 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
                   DETECTION/RECOVERY  
       714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING  
  
       714/1 .Reliability and availability  
       714/25 ..Fault locating (i.e., diagnosis or testing)  
  
       714/32 ...Particular stimulus creation
  
- 2 714/721 (1 OR, 1 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
                   DETECTION/RECOVERY  
       714/699 PULSE OR DATA ERROR HANDLING  
       714/718 .Memory testing  
       714/721 ..Electrical parameter (e.g., threshold  
                   voltage)
  
- 2 714/729 (1 OR, 1 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
                   DETECTION/RECOVERY  
       714/699 PULSE OR DATA ERROR HANDLING  
       714/724 .Digital logic testing  
       714/726 ..Scan path testing (e.g., level sensitive scan  
                   design (LSSD))  
       714/729 ...Plural scan paths
  
- 2 714/735 (0 OR, 2 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
                   DETECTION/RECOVERY  
       714/699 PULSE OR DATA ERROR HANDLING  
       714/724 .Digital logic testing  
       714/735 ..Device response compared to input pattern
  
- 2 716/4 (2 OR, 0 XR)  
 Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF  
                   CIRCUIT OR SEMICONDUCTOR MASK  
       716/1 CIRCUIT DESIGN  
       716/4 .Testing or evaluating